Agenda

- “News on the 130nm Technology”
  by Wojciech Bialas (CERN) (10’)

- “Design Toos, Flows and Library Aspects during the FE-I4 Implementation on Silicon”
  by Vladimir Zivkovic (NIKHEF Institute) (15’)

- “Noise and Radiation Hardness of 65nm CMOS Transistors and Pixel Front-Ends”
  by Massimo Manghisoni (University of Bergamo) (20’)

- Access of 65nm technology through CERN.
  by Kostas Kloukinas (CERN) (10’)

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